# DSA2G01

### Silicon PNP epitaxial planar type

#### For high-frequency amplification

### Features

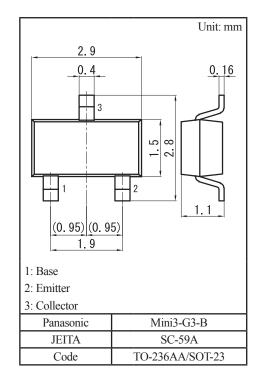
- $\bullet$  High transition frequency  $f_{\rm T}$
- Halogen-free / RoHS compliant
- (EU RoHS / UL-94 V-0 / MSL: Level 1 compliant)

#### Marking Symbol: A4

#### Packaging

DSA2G01×0L Embossed type (Thermo-compression sealing): 3 000 pcs / reel (standard)

#### Absolute Maximum Ratings $T_a = 25^{\circ}C$ Parameter Symbol Rating Unit V<sub>CBO</sub> Collector-base voltage (Emitter open) -30 V Collector-emitter voltage (Base open) $V_{\text{CEO}}$ -20V V Emitter-base voltage (Collector open) $V_{\text{EBO}}$ -5 -30 Collector current $I_{\rm C}$ mA 200 mW Collector power dissipation $\mathbf{P}_{\mathbf{C}}$ Junction temperature T<sub>i</sub> 150 °C °C Operating ambient temperature -40 to +85 Topr -55 to +150 Storage temperature °C T<sub>stg</sub>



#### Electrical Characteristics $T_a = 25^{\circ}C \pm 3^{\circ}C$

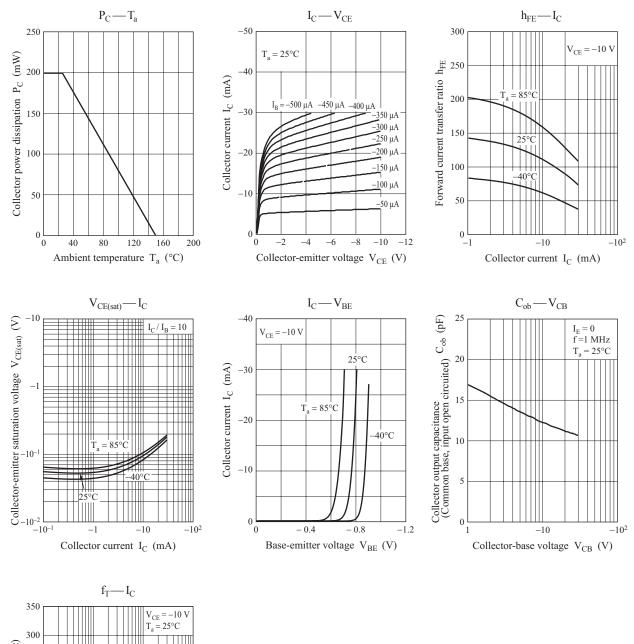
Parameter	Symbol	Conditions Min T		Тур	Max	Unit
Base-emitter voltage	V <sub>BE</sub>	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}$		- 0.7		V
Collector-base cutoff current (Emitter open)	I <sub>CBO</sub>	$V_{CB} = -10 \text{ V}, I_E = 0$			- 0.1	μΑ
Collector-emitter cutoff current (Base open)	I <sub>CEO</sub>	$V_{CE} = -20 \text{ V}, I_B = 0$			-100	μΑ
Emitter-base cutoff current (Collector open)	I <sub>EBO</sub>	$V_{EB} = -5 \text{ V}, I_C = 0$			-10	μΑ
Forward current transfer ratio *1	h <sub>FE</sub>	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}$	70		220	
Collector-emitter saturation voltage	V <sub>CE(sat)</sub>	$I_{\rm C} = -10 \text{ mA}, I_{\rm B} = -1 \text{ mA}$		- 0.1		V
Transition frequency	$\mathbf{f}_{\mathrm{T}}$	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}$	150	300		MHz
Reverse transfer capacitance (Common emitter)	C <sub>re</sub>	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}, f = 10.7 \text{ MHz}$		1.0		pF
Noise figure	NF	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}, f = 5 \text{ MHz}$		2.8		dB
Reverse transfer impedance	Z <sub>rb</sub>	$V_{CE} = -10 \text{ V}, I_C = -1 \text{ mA}, f = 2 \text{ MHz}$		22		Ω

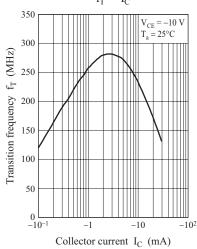
Note) 1. Measuring methods are based on JAPANESE INDUSTRIAL STANDARD JIS C 7030 measuring methods for transistors.

2. \*1: Rank classification

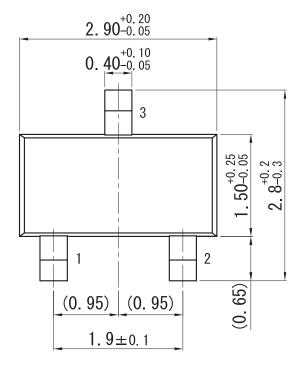
Code	В	С	0
Rank	В	С	No-rank
h <sub>FE</sub>	70 to 140	110 to 220	70 to 220
Marking Symbol	A4B	A4C	A4

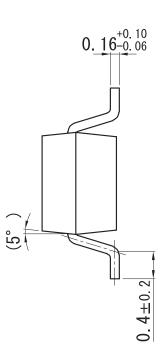
Product of no-rank is not classified and have no marking symbol for rank.

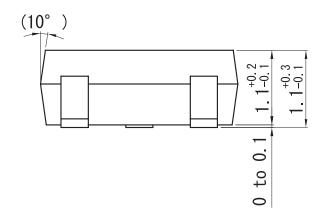




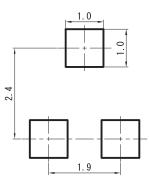
### Mini3-G3-B







Land Pattern (Reference) (Unit: mm)



Unit: mm

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